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Many-Layer Hotspot Detection by Layer-Attentioned Visual Question Answering

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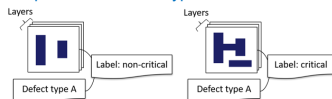


BACKGROUND & MOTIVATION

- Motivation**
 - Defects are generated due to the compounding effects from different process and inter-layer process variations

Problem: Many-Layer Hotspot Detection

- Critical pattern to a defect type



Challenges

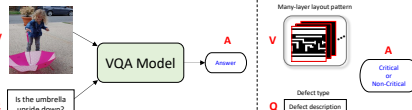
- 1) Pattern dimension varies for different defect types
- 2) Polygons of a hotspot pattern reside over many layers
- 3) The importance and relevance of each layer varies for different defect types



NEW INSIGHTS

Remodeling: Visual Question Answering (VQA)

- Answer if a pattern is critical to a specific defect type
- One model can answer all the defect types

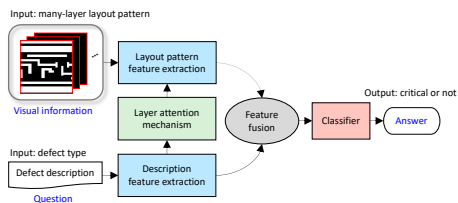


- Objective:** maximize the answering accuracy
- Solution: VQA with layer attention mechanism**
 - Identify the importance and relevance of each layer for different defect types

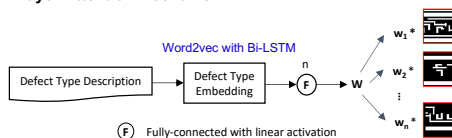
DESCRIPTION

Overall Pipeline of Our VQA System

1. Feature extraction: layout representation, sentence embedding neural network
2. Feature fusion: merge defect description and layout feature
3. Classifier: answer critical or non-critical
4. Layer attention mechanism: focus on the important layers

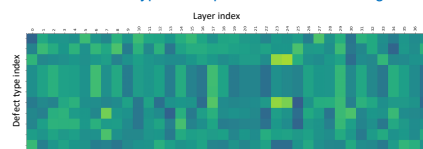


Layer Attention Mechanism



The Layered Relevance Weights of Partial Defect Types

- Similar defect type descriptions have similar weights



QUANTITATIVE IMPACT

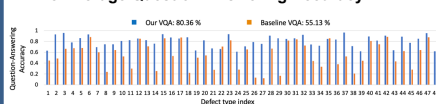
Dataset

- 7 layouts with sub-14nm process, 79,593 triple data
- V: a 38-layer layout pattern, Q: one of 57 defect types
- 80-20 split for training and testing

The accuracies for different defect types

Defect type category	A	B	C	D	E	F
# of patterns	1372	52	9159	2411	1738	664
Baseline VQA						
Testing accuracy	93.88 %	94.23 %	96.99 %	97.35 %	98.39 %	98.80 %
Miss	20	0	101	34	13	4
False alarm	64	3	175	30	15	4
Our VQA						
Testing accuracy	98.54 %	98.08 %	98.30 %	99.34 %	99.79 %	99.85 %
Miss	1	0	64	3	0	0
False alarm	19	1	101	13	4	1

The Average Question-Answering Accuracy



SUMMARY AND CONCLUSION

- We address a new **many-layer hotspot pattern extraction** challenge
- We investigate the **linkage between many-layer hotspot patterns and potentially induced defect types**
- This is the first work that models the hotspot pattern extraction task as a **Visual Question Answering** problem
- We devise a **layer-attended VQA model** to identify the relevance of each layer for different defect types
- Experimental results show that the proposed model has superior question-answering ability

BACKGROUND &
MOTIVATION

Current state-of-the-art. What problem are you trying to solve, or what improvement are you trying to make?



NEW
INSIGHTS

Describe what is new about your approach. Try to address technology gaps. Why should people care?



DESCRIPTION

Main objectives, concept, achievements, how it works, assumptions and limitations



QUANTITATIVE
IMPACT

What were your results and how do these compare with existing technologies / techniques? Insert table, graph etc.



SUMMARY AND
CONCLUSION

Conclusions. Conclusion. Final results of your work. Where is this leading, and what are the next steps?